## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination FUKUDA, MIKIO Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0162560 A1	08-2003	Kaneko, Yasuhiro	455/550
*	В	US-2004/0198477 A1	10-2004	Jung et al.	455/575.4
*	С	US-2004/0259592 A1	12-2004	Taneya et al.	455/556.1
*	D	US-2006/0262954 A1	11-2006	Lee et al.	381/380
*	Е	US-2003/0064688	04-2003	Mizuta et al.	455/90
*	F	US-2003/0064758	04-2003	Mizuta et al.	455/566
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	κ	US-			
	L	US-			*
	٠м	US-		·	

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004017532 A1	02-2004	World Intellect	LEE et al.	HO4B 1/38
	0.	WO 2004032566 A1	04-2004	World Intellect	LEE et al.	H04R 1/00
	Р	WO 200219759 A1	03-2002	World Intellect	KIM et al.	H04R 1/00
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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.